

FDW2503NZ

Dual N-Channel 2.5V Specified PowerTrench MOSFET

General Description

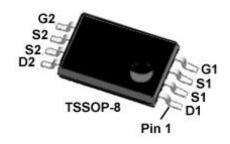
This NChannel 2.5V specified MOSFET is a rugged gate version of Fairchild Semiconductor's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V – 12V).

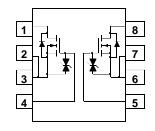
Applications

- Load switch
- Motor drive
- DC/DC conversion
- Power management

Features

- 5.5 A, 20 V. $R_{DS(ON)} = 20 \text{ m}\Omega \text{ @ V}_{GS} = 4.5 \text{V}$ $R_{DS(ON)} = 26 \text{ m}\Omega \text{ @ V}_{GS} = 2.5 \text{V}$
- Extended V_{GSS} range (±12V) for battery applications
- ESD protection diode (note 3)
- High performance trench technology for extremely low R_{DS(ON)}
- Low profile TSSOP-8 package





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		20	V
V _{GSS}	Gate-Source Voltage		±12	V
I _D	Drain Current - Continuous	(Note 1a)	5.5	A
	- Pulsed		30	
P _D	Power Dissipation	(Note 1a)	1.0	W
		(Note 1b)	0.6	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	100	°C/W
		(Note 1b)	125	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
2503NZ	FDW2503NZ	13"	12mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics			ı	ı	I.
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		14		mV/°C
l _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 16 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 12 \text{ V}, V_{DS} = 0 \text{ V}$			10	μΑ
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -12 \text{ V}, V_{DS} = 0 \text{ V}$			-10	μΑ
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	0.6	1.0	1.5	V
ΔV _{GS(th)} ΔT _J	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		-3		mV/°C
$R_{DS(on)}$	Static Drain–Source On–Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 5.5 \text{ A}$ $V_{GS} = 2.5 \text{ V}, I_D = 5 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 5.5 \text{ A}, T_J = 125 ^{\circ}\text{C}$		14 19 19	20 26 29	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	30			Α
G FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 5.5 \text{ A}$		30		S
Dynamic	Characteristics			•		•
Ciss	Input Capacitance	$V_{DS} = 10 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		1286		pF
Coss	Output Capacitance	f = 1.0 MHz		305		pF
C _{rss}	Reverse Transfer Capacitance	1		161		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 10 \text{ V}, \qquad I_D = 1 \text{ A},$		10	20	ns
t _r	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		14	25	ns
t _{d(off)}	Turn-Off Delay Time			25	40	ns
t _f	Turn-Off Fall Time			8	16	ns
Qg	Total Gate Charge	$V_{DS} = 10 \text{ V}, \qquad I_D = 5.5 \text{ A},$		12	17	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 4.5 \text{ V}$		2.6		nC
Q _{gd}	Gate-Drain Charge			3		nC
Drain-So	ource Diode Characteristics a	and Maximum Ratings				
Is	Maximum Continuous Drain-Source I	•			1.0	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.0 \text{ A}$ (Note 2)		0.7	1.2	V

Notes

- R_{BLR} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of
 the drain pins. R_{BLC} is guaranteed by design while R_{BCA} is determined by the user's board design.
 - a) $R_{\theta,JA}$ is 100°C/W (steady state) when mounted on a 1 inch² copper pad on FR-4.
 - b) $R_{\theta JA}$ is 125°C/W (steady state) when mounted on a minimum copper pad on FR-4.
- **2.** Pulse Test: Pulse Width < 300μ s, Duty Cycle < 2.0%
- 3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics

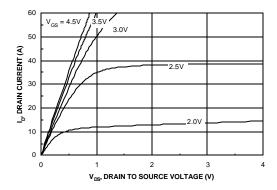


Figure 1. On-Region Characteristics.

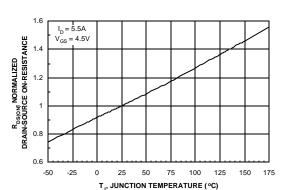


Figure 3. On-Resistance Variation with Temperature.

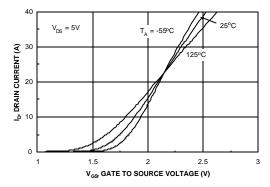


Figure 5. Transfer Characteristics.

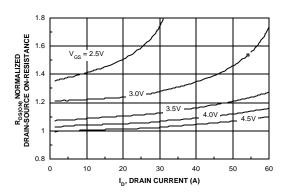


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

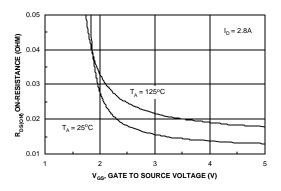


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

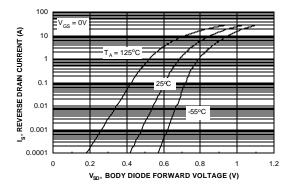
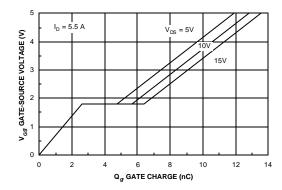


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



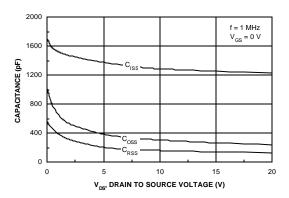
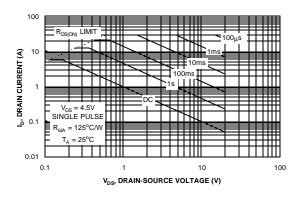


Figure 7. Gate Charge Characteristics.





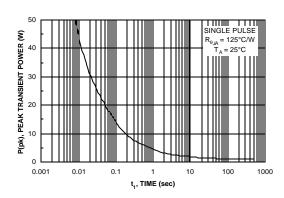


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

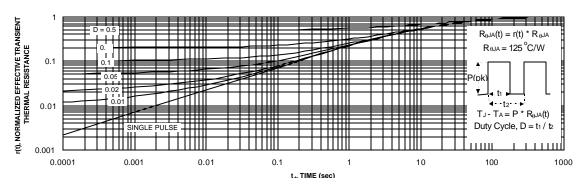


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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